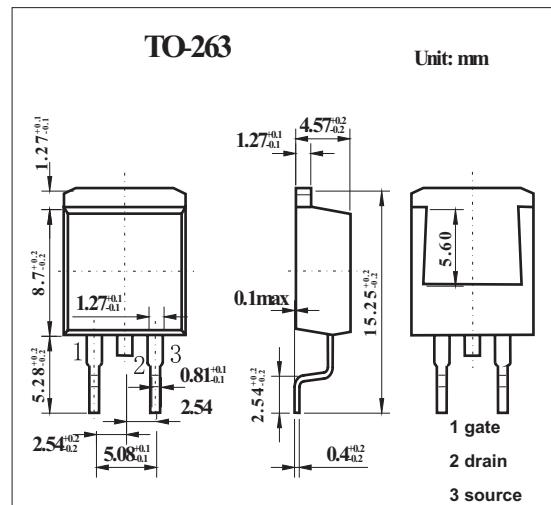
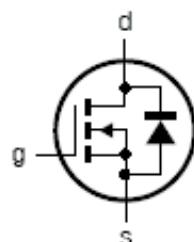


## TrenchMOS™ standard level FET

### KUK7607-30B

#### ■ Features

- Very low on-state resistance
- Q101 compliant
- 175°C rated
- Standard level compatible.



#### ■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	Rating	Unit
Drain-source voltage	V <sub>DS</sub>	30	V
Drain-gate voltage R <sub>GS</sub> = 20 kΩ	V <sub>DGR</sub>	30	V
Gate-source voltage	V <sub>GS</sub>	±20	V
Drain current (DC) T <sub>mb</sub> = 25°C, V <sub>GS</sub> = 10 V	I <sub>D</sub>	108	A
Drain current (DC) T <sub>mb</sub> = 100°C, V <sub>GS</sub> = 10 V	I <sub>D</sub>	75	A
Drain current (pulse peak value) *1	I <sub>DM</sub>	435	A
Total power dissipation T <sub>mb</sub> = 25°C	P <sub>tot</sub>	157	W
Storage & operating temperature	T <sub>stg</sub> , T <sub>j</sub>	-55 to 175	°C
reverse drain current (DC) T <sub>mb</sub> = 25°C	I <sub>DR</sub>	108	A
		75	A
pulsed reverse drain current *1	I <sub>DRM</sub>	435	A
non-repetitive avalanche energy *2	E <sub>DS(AL)S</sub>	329	J
Thermal resistance junction to mounting base	R <sub>th j-mb</sub>	0.95	K/W
Thermal resistance junction to ambient	R <sub>th j-a</sub>	50	K/W

\* 1 T<sub>mb</sub> = 25°C; pulsed; t<sub>p</sub> ≤ 10 μs;

\*2 unclamped inductive load; I<sub>D</sub> = 75 A; V<sub>DS</sub> ≤ 30 V; V<sub>GS</sub> = 10 V; R<sub>GS</sub> = 50Ω; starting T<sub>mb</sub> = 25°C

**KUK7607-30B**

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
drain-source breakdown voltage	V <sub>(BR)DSS</sub>	I <sub>D</sub> = 0.25 mA; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25°C	30			V
		I <sub>D</sub> = 0.25 mA; V <sub>GS</sub> = 0 V; T <sub>j</sub> = -55°C	27			V
gate-source threshold voltage	V <sub>GS(th)</sub>	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 25°C	2	3	4	V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 175°C	1			V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = -55°C			4.4	V
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> = 30 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25°C		0.02	1	μA
		V <sub>DS</sub> = 30 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 175°C			500	μA
gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> = ±20 V; V <sub>DS</sub> = 0 V		2	100	nA
drain-source on-state resistance	R <sub>DSON</sub>	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25°C	..	5.9	7	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 175°C			13.3	mΩ
total gate charge	Q <sub>G(tot)</sub>			36		nC
gate-to-source charge	Q <sub>GS</sub>	V <sub>GS</sub> = 10 V; V <sub>DD</sub> = 24 V; I <sub>D</sub> = 25 A		9		nC
gate-to-drain (Miller) charge	Q <sub>GD</sub>			12		nC
input capacitance	C <sub>ISS</sub>			1820	7446	pF
output capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 25 V; f = 1 MHz		632	1014	pF
reverse transfer capacitance	C <sub>rss</sub>			256	360	pF
turn-on delay time	t <sub>d(on)</sub>			20		ns
rise time	t <sub>r</sub>	V <sub>DD</sub> = 25 V; R <sub>L</sub> = 1.2Ω; V <sub>GS</sub> = 10 V; R <sub>G</sub> = 10Ω		51		ns
turn-off delay time	t <sub>d(off)</sub>			51		ns
fall time	t <sub>f</sub>			44		ns
internal drain inductance	L <sub>d</sub>			4.5		nH
	from drain lead 6 mm from package to centre of die		2.5		nH	
internal source inductance	L <sub>s</sub>	from source lead to source bond pad		7.5		nH
source-drain (diode forward) voltage	V <sub>SD</sub>	I <sub>S</sub> = 40A; V <sub>GS</sub> = 0 V		0.85	1.2	V
reverse recovery time	t <sub>rr</sub>	I <sub>S</sub> = 25 A; -dI/dt = -100 A/μs;		46		ns
recovered charge	Q <sub>r</sub>	V <sub>GS</sub> = -10 V; V <sub>DS</sub> = 20 V		28		nC